

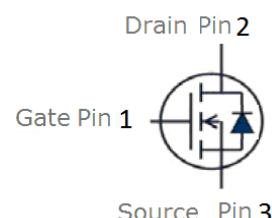
Features

- N-Channel, 10V Logic Level Control
- Enhancement mode
- Very low on-resistance $R_{DS(on)}$ @ $V_{GS}=10$ V
- 100% Avalanche test
- Pb-free lead plating; RoHS compliant

V_{DS}	80	V
$R_{DS(on),TYP}$ @ $V_{GS}=10$ V	7.2	$m\Omega$
I_D	105	A

TO-262


Part ID	Package Type	Marking	Tape and reel information
VS80N08AN	TO-262	80N08AN	50PCS/Tube



Maximum ratings, at $T_A = 25^\circ C$, unless otherwise specified

Symbol	Parameter		Rating	Unit
$V_{(BR)DSS}$	Drain-Source breakdown voltage		80	V
I_S	Diode continuous forward current	$T_A = 25^\circ C$	105	A
I_D	Continuous drain current@ $V_{GS}=10V$	$T_A = 25^\circ C$	105	A
		$T_A = 100^\circ C$	75	A
I_{DM}	Pulse drain current tested ①	$T_A = 25^\circ C$	420	A
EAS	Avalanche energy, single pulsed ②		319	mJ
P_D	Maximum power dissipation	$T_A = 25^\circ C$	156	W
V_{GS}	Gate-Source voltage		± 25	V
$T_{STG} T_J$	Storage and operating temperature range		-55 to 175	°C

Thermal Characteristics

Symbol	Parameter	Typical	Unit
$R_{\theta JC}$	Thermal Resistance-Junction to Case	0.96	°C/W
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient	62.5	°C/W



Symbol	Parameter	Condition	Min.	Typ.	Max.	Unit
Static Electrical Characteristics @ $T_j = 25^\circ\text{C}$ (unless otherwise stated)						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	80	--	--	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=80\text{V}, V_{\text{GS}}=0\text{V}$	--	--	1	μA
	Zero Gate Voltage Drain Current($T_j=125^\circ\text{C}$)	$V_{\text{DS}}=80\text{V}, V_{\text{GS}}=0\text{V}$	--	--	100	μA
I_{GSS}	Gate-Body Leakage Current	$V_{\text{GS}}=\pm 25\text{V}, V_{\text{DS}}=0\text{V}$	--	--	± 100	nA
$V_{\text{GS(TH)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	2.0	3.0	4.0	V
$R_{\text{DS(ON)}}$	Drain-Source On-State Resistance ^③	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=40\text{A}$	--	7.2	8	$\text{m}\Omega$
Dynamic Electrical Characteristics @ $T_j = 25^\circ\text{C}$ (unless otherwise stated)						
C_{iss}	Input Capacitance	$V_{\text{DS}}=30\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	--	4110	--	pF
C_{oss}	Output Capacitance		--	395	--	pF
C_{rss}	Reverse Transfer Capacitance		--	255	--	pF
R_g	Gate Resistance	$f=1\text{MHz}$	--	0.9	--	Ω
Q_g	Total Gate Charge	$V_{\text{DS}}=40\text{V}, I_{\text{D}}=40\text{A}, V_{\text{GS}}=10\text{V}$	--	70	--	nC
Q_{gs}	Gate-Source Charge		--	17	--	nC
Q_{gd}	Gate-Drain Charge		--	21	--	nC
Switching Characteristics						
$t_{\text{d(on)}}$	Turn-on Delay Time	$V_{\text{DD}}=40\text{V}, I_{\text{D}}=40\text{A}, R_{\text{C}}=3\Omega, V_{\text{GS}}=10\text{V}$	--	20	--	nS
t_r	Turn-on Rise Time		--	37	--	nS
$t_{\text{d(off)}}$	Turn-Off Delay Time		--	46	--	nS
t_f	Turn-Off Fall Time		--	25	--	nS
Source- Drain Diode Characteristics@ $T_j = 25^\circ\text{C}$ (unless otherwise stated)						
V_{SD}	Forward on voltage	$I_{\text{SD}}=40\text{A}, V_{\text{GS}}=0\text{V}$	--	0.9	1.2	V
t_{rr}	Reverse Recovery Time	$T_j=25^\circ\text{C}, I_{\text{SD}}=40\text{A}, V_{\text{GS}}=0\text{V}$ $dI/dt=100\text{A}/\mu\text{s}$	--	55	--	nS
Q_{rr}	Reverse Recovery Charge			100		nC

NOTE:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by $T_{j\text{max}}$, starting $T_j = 25^\circ\text{C}$, $L = 0.5\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 28\text{A}$, $V_{GS} = 10\text{V}$. Part not recommended for use above this value
- ③ Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$.



Vanguard
Semiconductor

VS80N08AN

80V/105A N-Channel Advanced Power MOSFET

Typical Characteristics

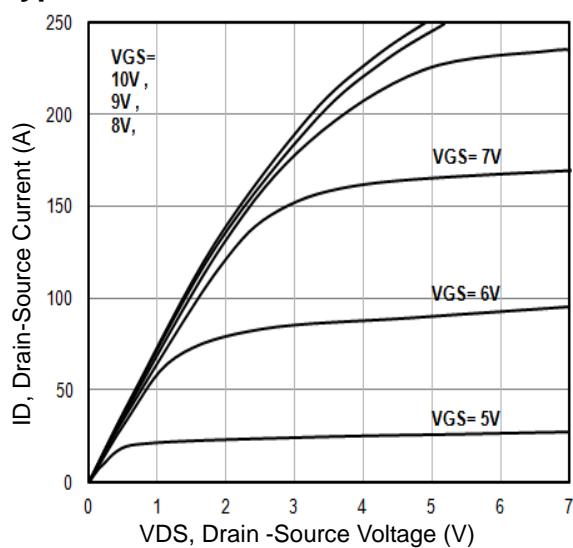


Fig1. Typical Output Characteristics

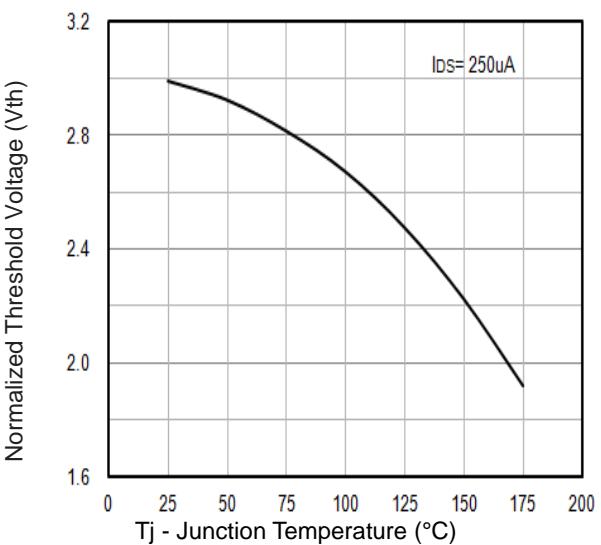


Fig2. $V_{GS(TH)}$ Gate-Source Voltage Vs. T_j

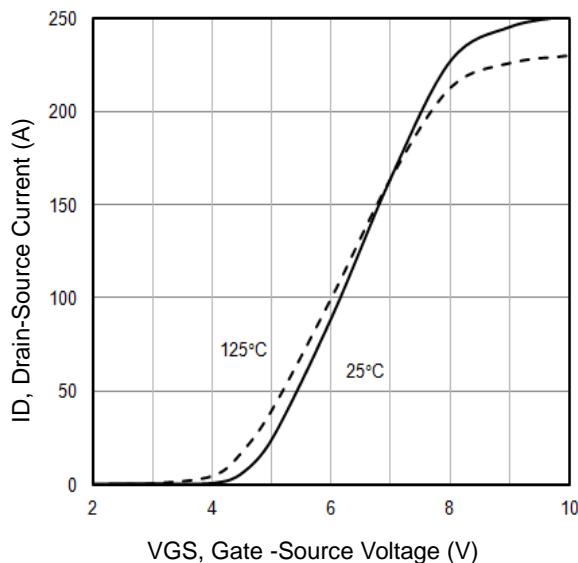


Fig3. Typical Transfer Characteristics

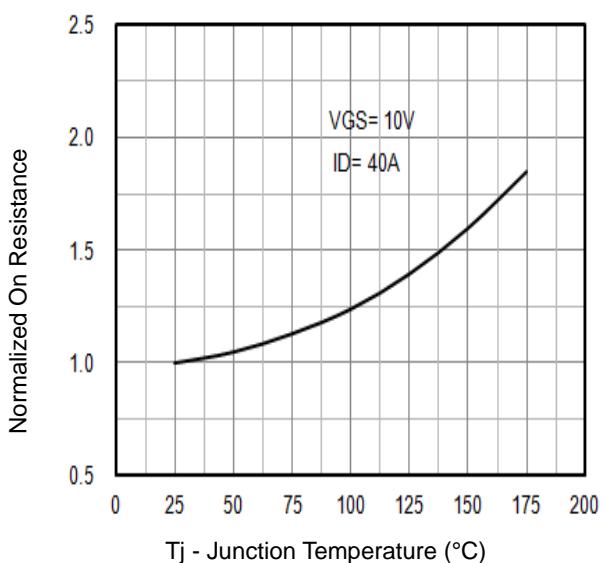


Fig4. Normalized On-Resistance Vs. T_j

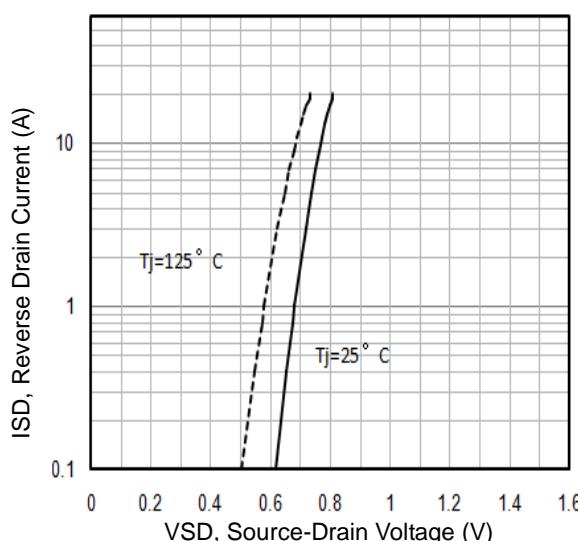


Fig5. Typical Source-Drain Diode Forward Voltage

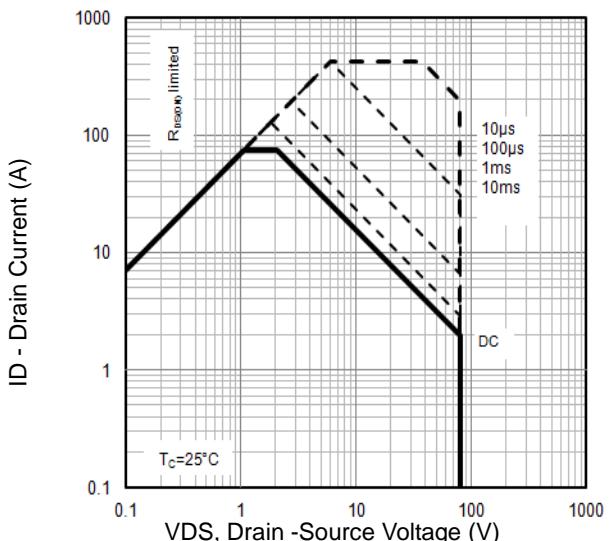


Fig6. Maximum Safe Operating Area



Typical Characteristics

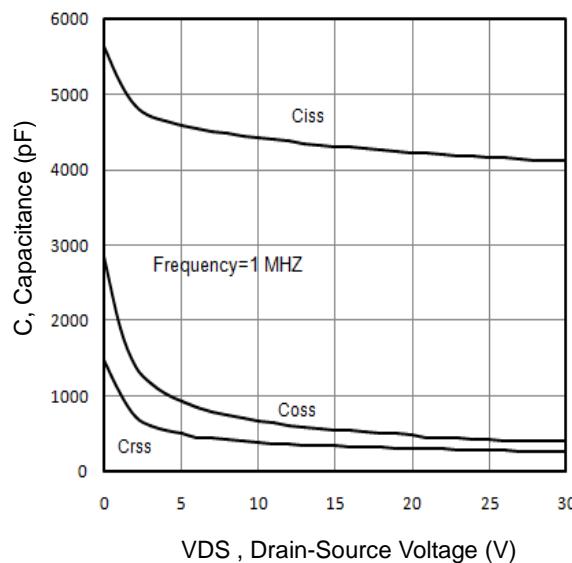


Fig7. Typical Capacitance Vs.Drain-Source Voltage

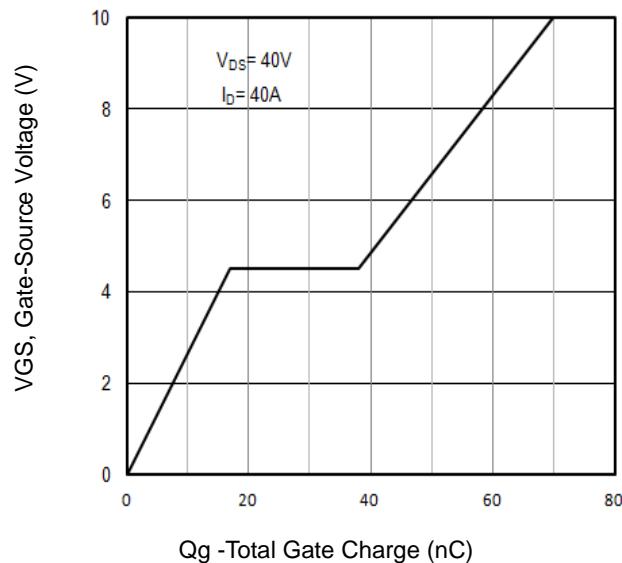


Fig8. Typical Gate Charge Vs.Gate-Source Voltage

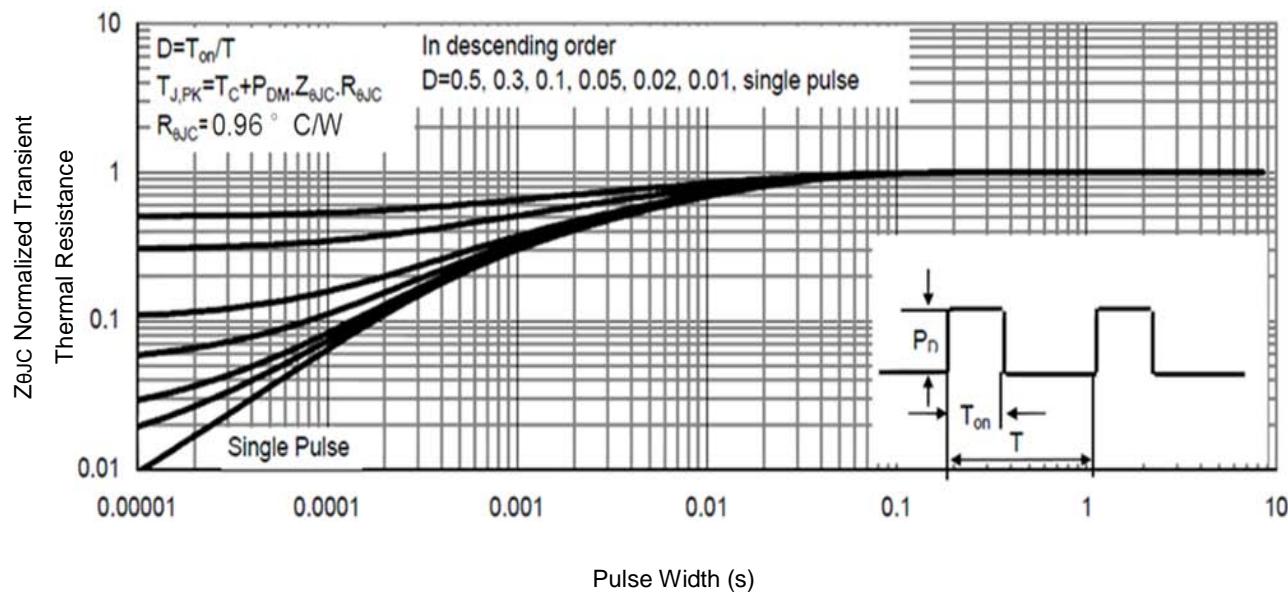


Fig9 . Normalized Maximum Transient Thermal Impedance

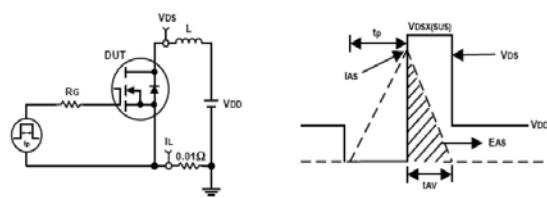


Fig10. Unclamped Inductive Test Circuit and waveforms

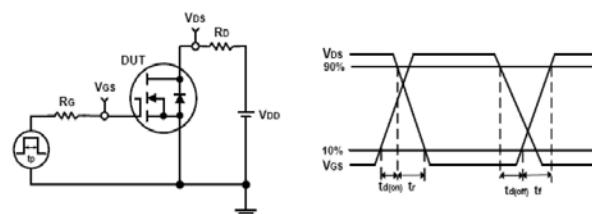
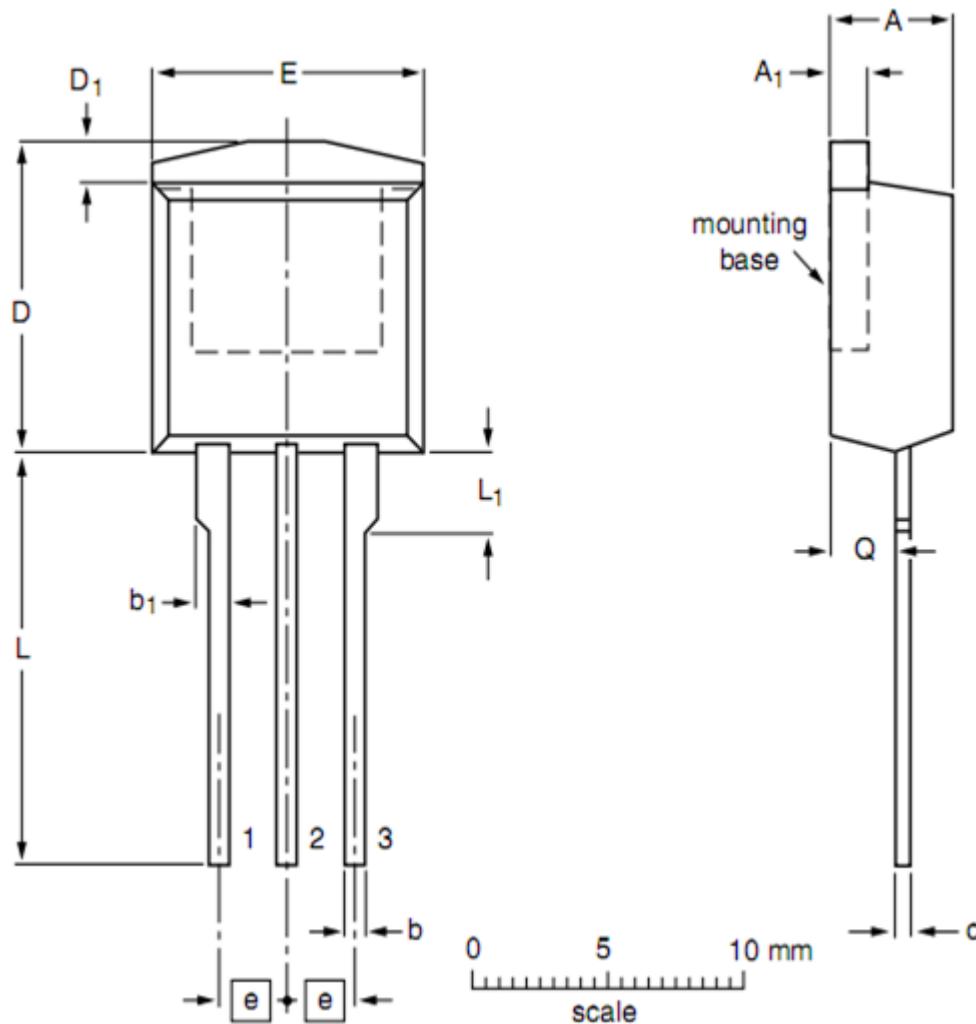


Fig11. Switching Time Test Circuit and waveforms



TO-262 Package Outline Data



Symbol	Dimensions (unit: mm)		
	Min	Typ	Max
A	4.10	4.47	4.83
A ₁	1.15	1.28	1.40
b	0.70	0.85	0.99
b ₁	1.20	1.30	1.40
c	0.46	0.58	0.70
D	9.80	10.40	11.00
D ₁	1.00	1.20	1.40
E	9.70	10.00	10.29
e	--	2.54	--
L	12.75	13.73	14.70
L ₁	--	3.10	3.30
Q	2.10	2.40	2.70

Note:

1. Refer to JEDEC TO-262.

Customer Service

Sales and Service:

sales@vgsemi.com

Vanguard Semiconductor CO., LTD

TEL: (86-755) -26902410

FAX: (86-755) -26907027

WEB: www.vgsemi.com